



FQB34P10TM_F085

100V P-Channel MOSFET

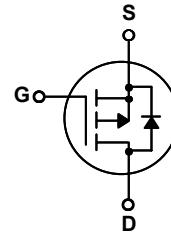
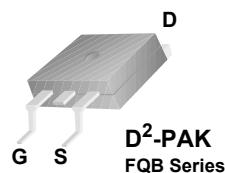
General Description

These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as audio amplifier, high efficiency switching DC/DC converters, and DC motor control.

Features

- 33.5A, -100V, $R_{DS(on)} = 0.06\Omega$ @ $V_{GS} = -10$ V
- Low gate charge (typical 85 nC)
- Low C_{rss} (typical 170 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- 175°C maximum junction temperature rating
- Qualified to AEC Q101
- RoHS Compliant



Absolute Maximum Ratings

$T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	FQB34P10TM_F085	Units
V_{DSS}	Drain-Source Voltage	-100	V
I_D	Drain Current - Continuous ($T_C = 25^\circ\text{C}$)	-33.5	A
	- Continuous ($T_C = 100^\circ\text{C}$)	-23.5	A
I_{DM}	Drain Current - Pulsed	(Note 1)	A
V_{GSS}	Gate-Source Voltage	± 25	V
E_{AS}	Single Pulsed Avalanche Energy	(Note 2)	mJ
I_{AR}	Avalanche Current	(Note 1)	A
E_{AR}	Repetitive Avalanche Energy	(Note 1)	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	V/ns
P_D	Power Dissipation ($T_A = 25^\circ\text{C}$) *	3.75	W
	Power Dissipation ($T_C = 25^\circ\text{C}$)	155	W
	- Derate above 25°C	1.03	W/ $^\circ\text{C}$
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to +175	$^\circ\text{C}$
T_L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	300	$^\circ\text{C}$

Thermal Characteristics

Symbol	Parameter	Typ	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	--	0.97	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *	--	40	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	--	62.5	$^\circ\text{C}/\text{W}$

* When mounted on the minimum pad size recommended (PCB Mount)

Electrical Characteristics		$T_C = 25^\circ\text{C}$ unless otherwise noted					
Symbol	Parameter	Test Conditions	Min	Typ	Max	Units	
Off Characteristics							
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}} = 0 \text{ V}$, $I_D = -250 \mu\text{A}$	-100	--	--	V	
$\Delta \text{BV}_{\text{DSS}} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = -250 \mu\text{A}$, Referenced to 25°C	--	-0.1	--	$\text{V}/^\circ\text{C}$	
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}} = -100 \text{ V}$, $V_{\text{GS}} = 0 \text{ V}$	--	--	-1	μA	
		$V_{\text{DS}} = -80 \text{ V}$, $T_C = 150^\circ\text{C}$	--	--	-10	μA	
I_{GSSF}	Gate-Body Leakage Current, Forward	$V_{\text{GS}} = -25 \text{ V}$, $V_{\text{DS}} = 0 \text{ V}$	--	--	-100	nA	
I_{GSSR}	Gate-Body Leakage Current, Reverse	$V_{\text{GS}} = 25 \text{ V}$, $V_{\text{DS}} = 0 \text{ V}$	--	--	100	nA	
On Characteristics							
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}} = V_{\text{GS}}$, $I_D = -250 \mu\text{A}$	-2.0	--	-4.0	V	
$R_{\text{DS(on)}}$	Static Drain-Source On-Resistance	$V_{\text{GS}} = -10 \text{ V}$, $I_D = -16.75 \text{ A}$	--	0.049	0.06	Ω	
g_{FS}	Forward Transconductance	$V_{\text{DS}} = -40 \text{ V}$, $I_D = -16.75 \text{ A}$ (Note 4)	--	23	--	S	
Dynamic Characteristics							
C_{iss}	Input Capacitance	$V_{\text{DS}} = -25 \text{ V}$, $V_{\text{GS}} = 0 \text{ V}$, $f = 1.0 \text{ MHz}$	--	2240	2910	pF	
C_{oss}	Output Capacitance		--	730	950	pF	
C_{rss}	Reverse Transfer Capacitance		--	170	220	pF	
Switching Characteristics							
$t_{\text{d(on)}}$	Turn-On Delay Time	$V_{\text{DD}} = -50 \text{ V}$, $I_D = -33.5 \text{ A}$, $R_G = 25 \Omega$	--	25	60	ns	
t_r	Turn-On Rise Time		--	250	510	ns	
$t_{\text{d(off)}}$	Turn-Off Delay Time		--	160	330	ns	
t_f	Turn-Off Fall Time		--	210	430	ns	
Q_g	Total Gate Charge	$V_{\text{DS}} = -80 \text{ V}$, $I_D = -33.5 \text{ A}$, $V_{\text{GS}} = -10 \text{ V}$	--	85	110	nC	
Q_{gs}	Gate-Source Charge		--	15	--	nC	
Q_{gd}	Gate-Drain Charge		--	45	--	nC	
Drain-Source Diode Characteristics and Maximum Ratings							
I_S	Maximum Continuous Drain-Source Diode Forward Current	--	--	-33.5	A		
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current	--	--	-134	A		
V_{SD}	Drain-Source Diode Forward Voltage	$V_{\text{GS}} = 0 \text{ V}$, $I_S = -33.5 \text{ A}$	--	--	-4.0	V	
t_{rr}	Reverse Recovery Time	$V_{\text{GS}} = 0 \text{ V}$, $I_S = -33.5 \text{ A}$, $dI_F / dt = 100 \text{ A}/\mu\text{s}$	--	160	--	ns	
Q_{rr}	Reverse Recovery Charge		--	0.88	--	μC	

Notes:

1. Repetitive Rating : Pulse width limited by maximum junction temperature
2. L = 3.9mH, $I_{AS} = -33.5\text{A}$, $V_{DD} = -25\text{V}$, $R_G = 25 \Omega$, Starting $T_J = 25^\circ\text{C}$
3. $I_{SD} \leq -33.5\text{A}$, $dI/dt \leq 300\text{A}/\mu\text{s}$, $V_{DD} \leq \text{BV}_{\text{DSS}}$, Starting $T_J = 25^\circ\text{C}$
4. Pulse Test : Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$
5. Essentially independent of operating temperature

Typical Characteristics

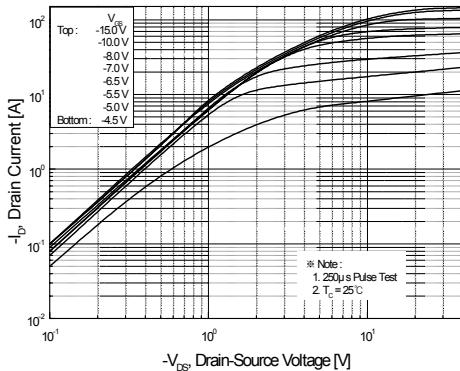


Figure 1. On-Region Characteristics

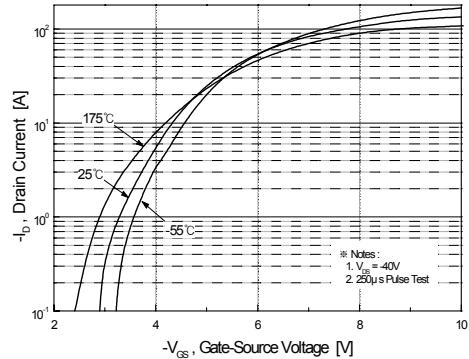


Figure 2. Transfer Characteristics

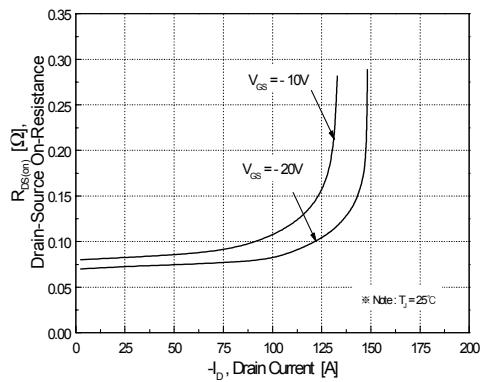


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

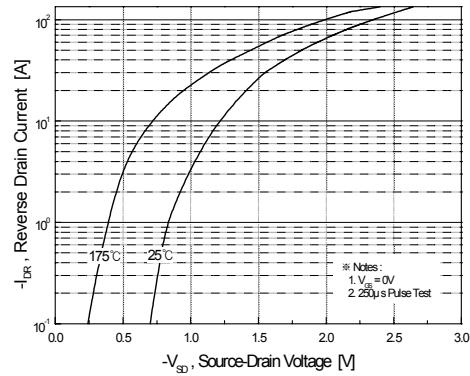


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

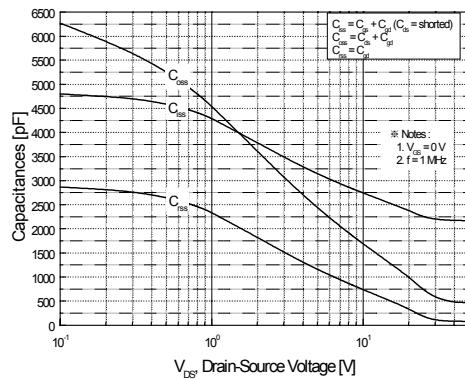


Figure 5. Capacitance Characteristics

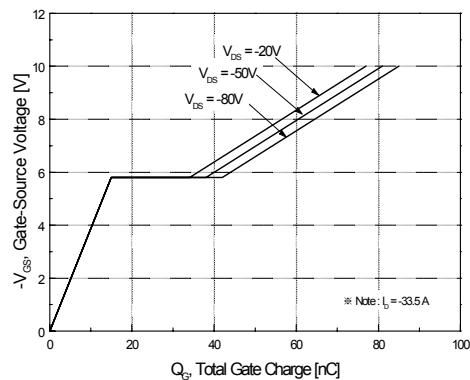


Figure 6. Gate Charge Characteristics